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#### 捷多邦,专业PCB打样工厂,24小时加急出货 AM26LV32 LOW-VOLTAGE HIGH-SPEED QUADRUPLE DIFFERENTIAL LINE RECEIVER SLLS202D - MAY 1995 - REVISED APRIL 2000

- Switching Rates up to 32 MHz
- Operates from a Single 3.3-V Supply
- Ultra-Low Power Dissipation . . . 27 mW Typ
- Open-Circuit, Short-Circuit, and Terminated Fail-Safe
- -0.3-V to 5.5-V Common-Mode Range With ±200 mV Sensitivity
- Accepts 5-V Logic Inputs With a 3.3-V V<sub>CC</sub>
- Input Hysteresis . . . 50 mV Typ
- 235 mW With Four Receivers at 32 MHz
- Pin-to-Pin Compatible With AM26C32, AM26LS32, and MB570



<sup>†</sup> The NS package is only available left-ended taped and reeled.

#### description

The AM26LV32, BiCMOS, quadruple, differential line receiver with 3-state outputs is designed to be similar to TIA/EIA-422-B and ITU Recommendation V.11 receivers with reduced common-mode voltage range due to reduced supply voltage.

The device is optimized for balanced bus transmission at switching rates up to 32 MHz. The enable function is common to all four receivers and offers a choice of active-high or active-low inputs. The 3-state outputs permit connection directly to a bus-organized system. Each device features receiver high input impedance and input hysteresis for increased noise immunity, and input sensitivity of  $\pm 200 \text{ mV}$  over a common-mode input voltage range from -0.3 V to 5.5 V. When the inputs are open circuited, the outputs are in the high logic state. This device is designed using the Texas Instruments (TI<sup>M</sup>) proprietary LinIMPACT-C60<sup>M</sup> technology, facilitating ultra-low power consumption without sacrificing speed.

This device offers optimum performance when used with the AM26LV31 quadruple line drivers.

The AM26LV32C is characterized for operation from 0°C to 70°C.

		FUNCTION TABLE (each receiver)					
	DIFFERENTIAL	ENA	BLES				
	INPUT	G	G	OUTPUT			
	$V_{ID} \ge 0.2 V$	H X	X L	H H			
	$-0.2 V < V_{ID} < 0.2 V$	H X	X L	? ?			
	$V_{ID} \leq -0.2 V$	H X	X L				
	Open, shorted, or terminated <sup>‡</sup>	H X	X L	н			
l	X	L	Н	Z			

H = high level, L = low level, X = irrelevant,

Z = high impedance (off), ? = indeterminate

<sup>‡</sup> See application information attached.

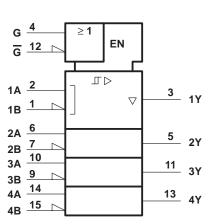


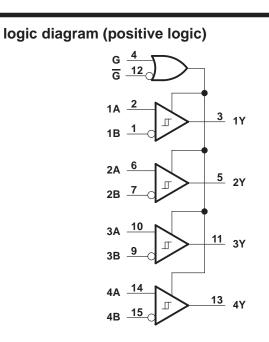
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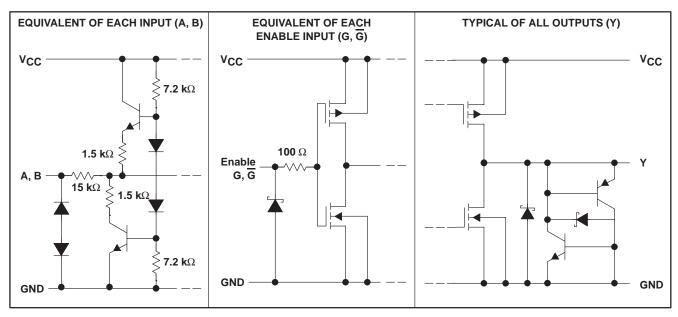
logic symbol<sup>†</sup>





<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

## schematics of equivalent inputs and outputs





### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)<sup>†</sup>

Supply voltage range, V <sub>CC</sub> (see Note 1)	
Input voltage range, V <sub>I</sub> (A or B inputs)	−4 V to 8 V
Differential input voltage, V <sub>ID</sub> (see Note 2)	±12 V
Enable input voltage range	$\dots \dots -0.3$ V to 6 V
Output voltage range, V <sub>O</sub>	$\dots \dots -0.3$ V to 6 V
Maximum output current, I <sub>O</sub>	±25 mA
Package thermal impedance, $\theta_{JA}$ (see Note 3): D package	73°C/W
NS package	64°C/W
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C
Storage temperature range, T <sub>stg</sub>	$\dots -65^{\circ}C$ to $150^{\circ}C$

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values are with respect to the GND terminal.
  - 2. Differential input voltage is measured at the noninverting input with respect to the corresponding inverting input.
  - 3. The package thermal impedance is calculated in accordance with JESD 51.

#### recommended operating conditions

		MIN	NOM	MAX	UNIT
Supply voltage, V <sub>CC</sub>		3	3.3	3.6	V
High-level input voltage, VIH(EN)		2			V
Low-level input voltage, VIL(EN)				0.8	V
Common-mode input voltage, VIC		-0.3		5.5	V
Differential input voltage, VID				±5.8	
High-level output current, I <sub>OH</sub>				-5	mA
Low-level output current, IOL				5	mA
Operating free-air temperature, T <sub>A</sub>	AM26LV32C	0		70	°C



### electrical characteristics over recommended supply-voltage and operating free-air temperature ranges (unless otherwise noted)

	PARAMETER	TEST C	ONDITIONS	MIN	түр†	MAX	UNIT
VIT+	Differential input high-threshold voltage					0.2	V
VIT-	Differential input low-threshold voltage			-0.2			V
VIK	Enable input clamp voltage	lj = - 18 mA			-0.8	-1.5	V
VOH	High-level output voltage	V <sub>ID</sub> = 200 mV,	I <sub>OH</sub> = -5 mA	2.4	3.2		V
VOL	Low-level output voltage	$V_{ID} = -200 \text{ mV},$	I <sub>OL</sub> = 5 mA		0.17	0.5	V
IOZ	High-impedance-state output current	$V_{O} = 0$ to $V_{CC}$				±50	μA
I <sub>IH(E)</sub>	High-level enable input current	$V_{CC} = 0 \text{ or } 3 \text{ V},$	V <sub>I</sub> = 5.5 V			10	μA
I <sub>IL(E)</sub>	Low-level enable input current	V <sub>CC</sub> = 3.6 V,	$V_{I} = 0 V$			-10	μΑ
rj	Input resistance			7	12		kΩ
Ц	Input current	$V_{I} = 5.5 V \text{ or } -0.3 V,$	All other inputs GND			±700	μA
ICC	Supply current	$V_{I(E)} = V_{CC} \text{ or } GND,$	No load, line inputs open		8	17	mA
C <sub>pd</sub>	Power dissipation capacitance <sup>‡</sup>	One channel			150		pF

<sup>†</sup> All typical values are at V<sub>CC</sub> = 3.3 V and T<sub>A</sub> = 25°C. <sup>‡</sup> C<sub>pd</sub> determines the no-load dynamic current:  $I_S = C_{pd} \times V_{CC} \times f + I_{CC}$ .

# switching characteristics, $V_{CC}$ = 3.3 V, $T_A$ = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
<sup>t</sup> PLH	Propagation delay time, low- to high-level output	See Figure 1	8	16	20	ns
<sup>t</sup> PHL	Propagation delay time, high- to low-level output	See Figure 1	8	16	20	ns
tt	Transistion time (t <sub>r</sub> or t <sub>f</sub> )	See Figure 1		5		ns
<sup>t</sup> PZH	Output-enable time to high level	See Figure 2		17	40	ns
t <sub>PZL</sub>	Output-enable time to low level	See Figure 3		10	40	ns
<sup>t</sup> PHZ	Output-disable time from high level	See Figure 2		20	40	ns
<sup>t</sup> PLZ	Output-disable time from low level	See Figure 3		16	40	ns
<sup>t</sup> sk(p) <sup>§</sup>	Pulse skew			4	6	ns
t <sub>sk(o)</sub> ¶	Pulse skew			4	6	ns
<sup>t</sup> sk(pp) <sup>#</sup>	Pulse skew (device to device)			6	9	ns

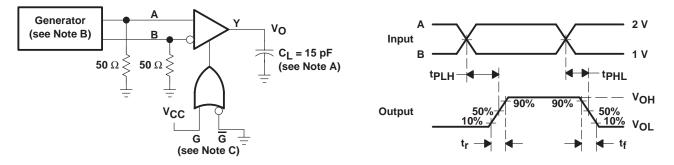
§ tsk(p) is |tpLH - tpHL| of each channel of the same device.
It tsk(o) is the maximum difference in propagation delay times between any two channels of the same device switching in the same direction.
# tsk(pp) is the maximum difference in propagation delay times between any two channels of any two devices switching in the same direction.



#### AM26LV32 LOW-VOLTAGE HIGH-SPEED QUADRUPLE DIFFERENTIAL LINE RECEIVER

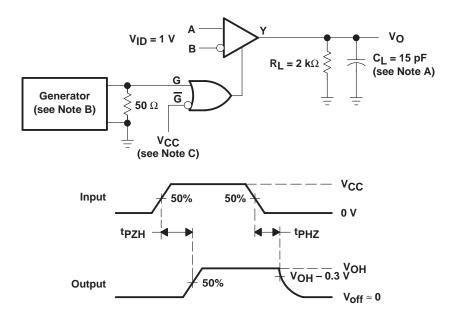
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### PARAMETER MEASUREMENT INFORMATION



- NOTES: A. CL includes probe and jig capacitance.
  - B. The input pulse is supplied by a generator having the following characteristics:  $Z_0 = 50 \Omega$ , PRR = 10 MHz,  $t_f$  and  $t_f$  (10% to 90%) ≤ 2 ns, 50% duty cycle.
  - C. To test the active-low enable  $\overline{G}$ , ground G and apply an inverted waveform  $\overline{G}$ .

#### Figure 1. tPLH and tPHL Test Circuit and Voltage Waveforms

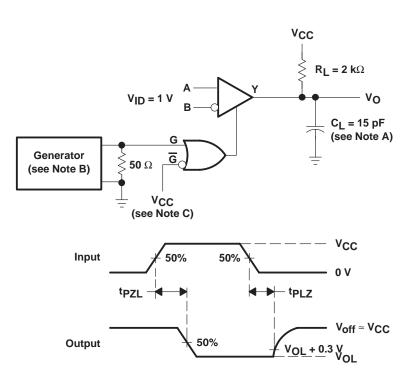


- NOTES: A. CL includes probe and jig capacitance.
  - B. The input pulse is supplied by a generator having the following characteristics:  $Z_0 = 50 \Omega$ , PRR = 10 MHz,  $t_f$  (10% to 90%)  $\leq$  2 ns, 50% duty cycle.
  - C. To test the active-low enable  $\overline{G}$ , ground G and apply an inverted waveform  $\overline{G}$ .

### Figure 2. tp7H and tpH7 Test Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION



- NOTES: A. CL includes probe and jig capacitance.
  - B. The input pulse is supplied by a generator having the following characteristics:  $Z_0 = 50 \Omega$ , PRR = 10 MHz,  $t_f$  and  $t_f$  (10% to 90%)  $\leq$  2 ns, 50% duty cycle.
  - C. To test the active-low enable  $\overline{G}$ , ground G and apply an inverted waveform  $\overline{G}$ .

Figure 3.  $t_{PZL}$  and  $t_{PLZ}$  Test Circuit and Voltage Waveforms



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### **APPLICATION INFORMATION**

#### fail-safe conditions

The AM26LV32 guadruple differential line receiver is designed to function properly when appropriately connected to active drivers. Applications do not always have ideal situations where all bits are being used, the receiver inputs are never left floating, and fault conditions don't exist. In actuality, most applications have the capability to either place the drivers in a high-impedance mode or power down the drivers altogether, and cables may be purposely (or inadvertently) disconnected, both of which lead to floating receiver inputs. Furthermore, even though measures are taken to avoid fault conditions like a short between the differential signals, this does occur. The AM26LV32 has an internal fail-safe circuitry which prevents the device from putting an unknown voltage signal at the receiver outputs. In the following three cases, a high-state is produced at the respective output:

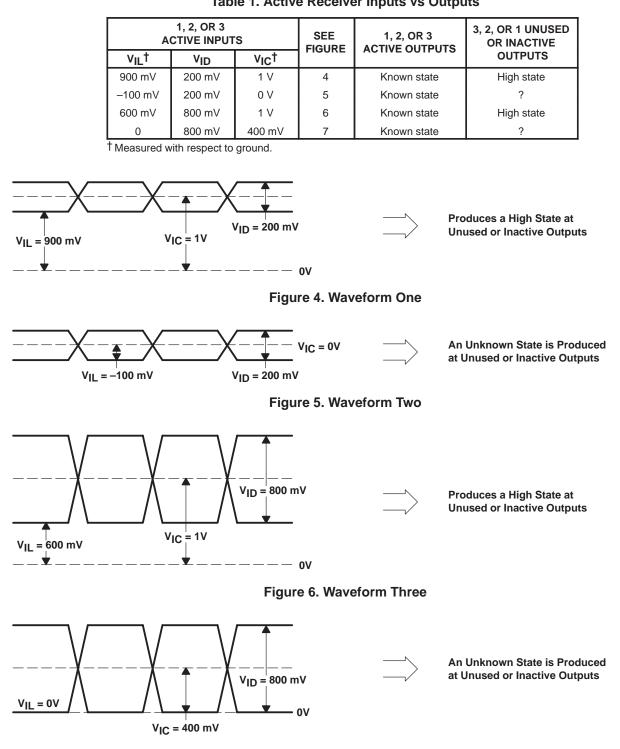
- 1. Open fail-safe Unused input pins are left open. Do not tie unused pins to ground or any other voltage. Internal circuitry places the output in the high state.
- 2. 100-ohm terminated fail-safe Disconnected cables, drivers in high-impedance state, or powered-down drivers will not cause the AM26LV32 to malfunction. The outputs will remain in a high state under these conditions. When the drivers are either turned-off or placed into the high-impedance state, the receiver input may still be able to pick up noise due to the cable acting as an antenna. To avoid having a large differential voltage being generated, the use of twisted-pair cable will induce the noise as a common-mode signal and will be rejected.
- Shorted fail-safe Fault conditions that short the differential input pairs together will not cause incorrect data at the outputs. A differential voltage (VID) of 0 V will force a high state at the outputs. Shorted fail-safe, however, is not supported across the recommended common-mode input voltage (VIC) range. An unwanted state can be induced to all outputs when an input is shorted and is biased with a voltage between -0.3 V and 5.5 V. The shorted fail-safe circuitry will function properly when an input is shorted, but with no external common-mode voltage applied.

#### fail-safe precautions

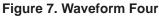
The internal fail-safe circuitry was designed such that the input common-mode ( $V_{IC}$ ) and differential (V<sub>ID</sub>)voltages must be observed. In order to ensure the outputs of unused or inactive receivers remain in a high state when the inputs are open-circuited, shorted, or terminated, extra precaution must be taken on the active signal. In applications where the drivers are placed in a high-impedance mode or are powered-down, it is recommended that for 1, 2, or 3 active receiver inputs, the low-level input voltage (VII) should be greater than 0.4 V. As in all data transmission applications, it is necessary to provide a return ground path between the two remote grounds (driver and receiver ground references) to avoid ground differences. Table 1 and Figures 4 through 7 are examples of active input voltages with their respective waveforms and the effect each have on unused or inactive outputs. Note that the active receivers behave as expected, regardless of the input levels.



**APPLICATION INFORMATION** 



#### Table 1. Active Receiver Inputs vs Outputs





### **APPLICATION INFORMATION**

In most applications, it is not customary to have a common-mode input close to ground and to have a differential voltage larger than 2 V. Since the common-mode input voltage is typically around 1.5 V, a 2-V V<sub>ID</sub> would result in a V<sub>IL</sub> of 0.5 V, thus satisfying the recommended V<sub>IL</sub> level of greater than 0.4 V.

Figure 8 plots seven different input threshold curves from a variety of production lots and shows how the fail-safe circuitry behaves with the input common-mode voltage levels. These input threshold curves are representative samples of production devices. The curves specifically illustrate a typical range of input threshold variation. The AM26LV32 is specified with  $\pm 200 \text{ mV}$  of input sensitivity to account for the variance in input threshold. Each data point represents the input's ability to produce a known state at the output for a given  $V_{IC}$  and  $V_{ID}$ . Applying a differential voltage at or above a certain point on a curve would produce a known state at the output. Applying a differential voltage less than a certain point on a curve would activate the fail-safe circuit and the output would be in a high state. For example, inspecting the top input threshold curve reveals that for a  $V_{IC} = 1.6 \text{ V}$ ,  $V_{ID}$  yields around 87 mV. Applying 90 mV of differential voltage to this particular production lot generates a known receiver output voltage. Applying a  $V_{ID}$  of 80 mV activates the input fail-safe circuitry and the receiver output is placed in the high state. Texas Instruments specifies the input voltages around 0.2 V, the input differential voltages are low compared to their respective data points. This phenomenon points to the fact that the inputs are very sensitive to small differential voltages around 0.2 V  $V_{IC}$ . It is recommended that  $V_{IC}$  levels be kept greater than 0.5 V to avoid this increased sensitivity at  $V_{IC} \approx 0.2 \text{ V}$ . In most applications, since  $V_{IC}$  typically is 1.5 V, the fail-safe circuitry functions properly to provide a high state at the receiver output.

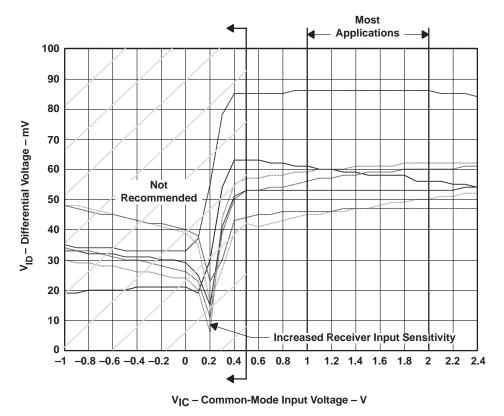


Figure 8. VIC Versus VID Receiver Sensitivity Levels



**APPLICATION INFORMATION** 

Figure 9 represents a typical application where two receivers are not used. In this case, there is no need to worry about the output voltages of the unused receivers since they are not connected in the system architecture.

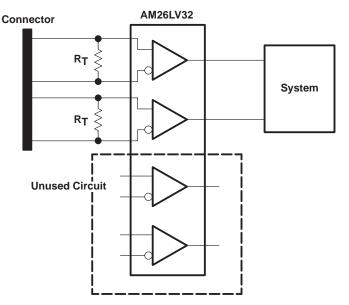


Figure 9. Typical Application with Unused Receivers

Figure 10 shows a common application where one or more drivers are either disabled or powered down. To ensure the inactive receiver outputs are in a high state, the active receiver inputs must have  $V_{IL} > 0.4$  V and  $V_{IC} > 0.5$  V.

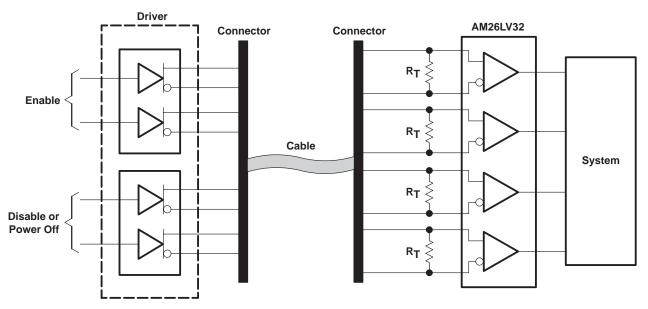


Figure 10. Typical Application Where Two or More Drivers are Disabled



### **APPLICATION INFORMATION**

Figure 11 is an alternative application design to replace the application in Figure 10. This design uses two AM26LV32 devices, instead of one. However, this design does not require the input levels be monitored to ensure the outputs are in the correct state, only that they comply to the RS-232 standard.

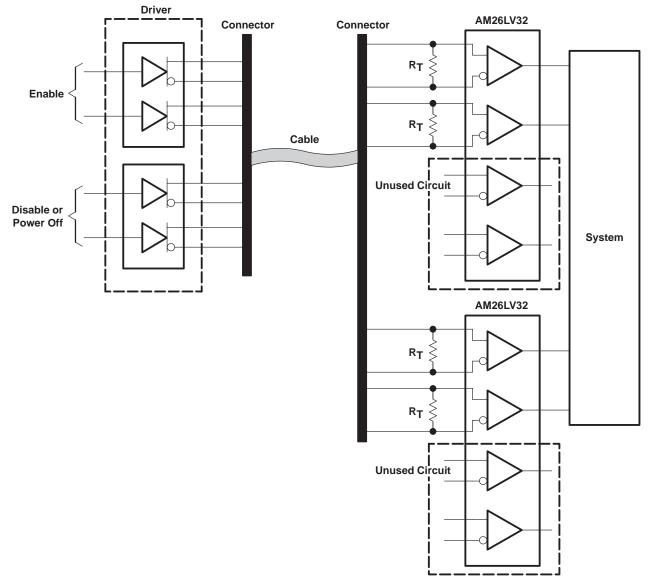


Figure 11. Alternative Solution for Figure 10



**APPLICATION INFORMATION** 

Figures 12 and 13 show typical applications where a disconnected cable occurs. Figure 12 illustrates a typical application where a cable is disconnected. Similar to Figure 10, the active input levels must be monitored to make sure the inactive receiver outputs are in a high state. An alternative solution is shown in Figure 13.

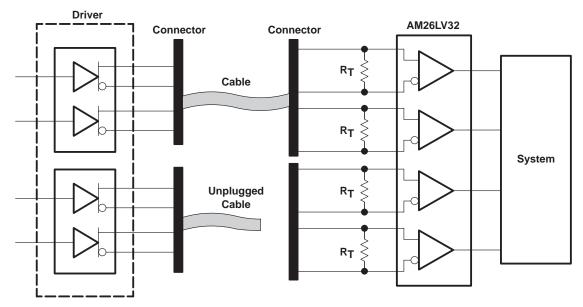


Figure 12. Typical Application Where Two or More Drivers are Disconnected



## **APPLICATION INFORMATION**

Figure 13 is an alternative solution so the receiver inputs do not have to be monitored. This solution also requires the use of two AM26LV32 devices, instead of one.

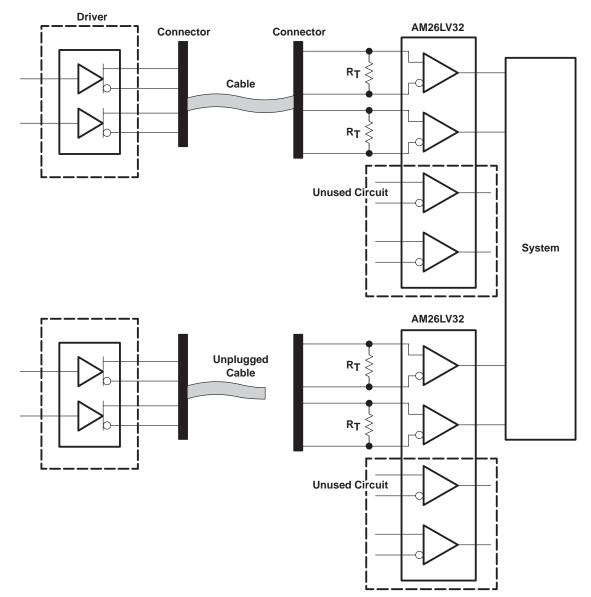


Figure 13. Alternative Solution to Figure 12



**APPLICATION INFORMATION** 

When designing a system using the AM26LV32, the device provides a robust solution where fail-safe and fault conditions are of concern. The RS-422-like inputs accept common-mode input levels from -0.3 V to 5.5 V with a specified sensitivity of  $\pm 200$ mV. As previously shown, care must be taken with active input levels since they can affect the outputs of unused or inactive bits. However, most applications meet or exceed the requirements to allow the device to perform properly.



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